

RT-3000/RG-2000(RG-3000) SEMI-AUTO SHEET RESISTANCE/RESISTIVITY MEASUREMENT

RT-3000/RG-2000(RG-3000)



- Multi-point, Contact Type PC controlled via software
- Wide measure range and high accuracy using 4-point probe method
- User programmable measurement pattern
- Tester self-test function
- Thickness, edge, temperature correction for silicon wafer
- Film thickness conversion function from sheet resistance
- Measure Range (RT-3000/S version):
 - ✓ Resistivity: 0.1mΩ.cm to 1MΩ.cm
 - ✓ Sheet Resistance: 1mΩ/sq to 10MΩ/sq
- Measure Range (RT-3000/H version):
 - ✓ Sheet Resistance: 10mΩ/sq to 1GΩ/sq
- Sample Size:
 - ✓ WS-8800: Ø 8", 156mm x 156mm
 - ✓ WS-3000: Ø 3" to 12" (Optional Ø 8")
 - ✓ Optional RG-3000: Ø 12", 210mm x 210mm

APPLICABLE MATERIALS

- Semiconductor and Solar-cell materials (Silicon, Polysilicon, SiC etc)
- Functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
- Conductive thin film (Metal, ITO etc)
- Diffused sample (or layer)
- Silicon-related thin films (LTPS etc), IGZO
- Silicon-related epitaxial materials, Ion-implantation sample
- Others: On Request

